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SP02-274 PTO-1449 (MODIFIED) ATTORNEY DOCKET NO. SERIAL NO. LIST OF PATENTS AND SP02-274 10/677450 **PUBLICATIONS** FOR APPLICANTS INFORMATION **DISCLOSURE STATEMENT** APPLICANT DOWNIE JOHN D, et al. 2613 FILING DATE 10/2/2003 GROUP: 2877-REFERENCE DESIGNATION U.S. PATENT DOCUMENTS Filing Date Examiner **Document Number** Date Name Class Subif Approp. Initial Class AA ABAC AD AE AF AG AH ΑI AJ AK FOREIGN PATENT DOCUMENTS

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HP	AR	Downie et al.; "Performance monitoring of optical networks with synchronous and asynchronous sampling"; Optical Fiber Communication Conference; March 17-22, 2001; Volume 54
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